



New Developments in Microanalytical Techniques for Electron Microscopy

Thursday, June 3, 2010
10:00 AM – 3:30 PM

Hosted By:

Glenn Kinnear & Ruth Murray – Oxford Instruments
Rich Fiore - Protochips

Guest Speakers

Dr. John Armstrong, Carnegie Institution
Dr. Nicholas Ritchie, NIST

AGENDA

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| 9:30 – 10:00 AM | Registration / Welcome |
| 10:00 AM | Dr. John Armstrong, <i>Thin Film Analysis</i> |
| Break | |
| 11:00 AM | Dr. Richard McLaughlin, <i>Latest Developments in Silicon Drift Detectors</i> |
| Noon | Lunch (Courtesy of Oxford Instruments / Carnegie Institution Lab Tour) |
| 1:00 PM | Dr. Nicholas Ritchie, <i>DTSA-II: Power Tools for X-Ray Microanalysis</i> |
| Break | |
| 2:00 PM | Dr. Richard McLaughlin, <i>EBSD Applications & Capabilities</i> |
| 3:00 PM | Rich Fiore, <i>New Capabilities in Electron Microscopy Using In Situ Heating</i> |

Location:

Abelson Building, Lower Level Conference Suite
Carnegie Institution of Washington
5251 Broad Branch Road, NW
Washington, DC

The Abelson Building of the Carnegie Institution of Washington is located at the Broad Branch Road Campus in Washington, DC (<http://www.gi.ciw.edu/about/directions>)

To register or for more information please contact Nancy Crouch at nancy.crouch@oxinst.com or 1-800-447-4717 ext. 105